CLAIMS

[Claim 1] A probe having, at one end in a longitudinal direction, a contact portion to contact with an electrode of an inspection target, and having, at another end in the longitudinal direction, a terminal portion to contact with a circuit board, the probe comprising:

a low-resistance portion made of a first metal that is conductive;

a high-resistance portion made of a second metal that is conductive and has a higher resistivity than a resistivity of the low-resistance portion; and

a middle-resistance portion made of a third metal having a lower resistivity than the resistivity of the high-resistance portion and having a higher resistivity than the resistivity of the low-resistance portion, wherein

the probe has

a low-high resistance portion formed such that, in a cross-section perpendicular to a longitudinal direction of the probe, a periphery of the low-resistance portion is coated with the high-resistance portion, and

a middle-high resistance portion which is located on the contact portion side of the low-high resistance portion and which, in a cross-section perpendicular to the longitudinal direction of the probe, has the middle-resistance portion and the high-resistance

portion, and

in the middle-high resistance portion,

the middle-resistance portion is connected with the low-resistance portion in the longitudinal direction of the probe, and

the middle-resistance portion is interposed between, on both side surfaces in a buckling direction of the probe, the high-resistance portions extending continuously from the high-resistance portion of the low-high resistance portion.

[Claim 2] The probe according to claim 1, wherein

the high-resistance portion of the middle-high resistance portion is embedded, along the longitudinal direction of the probe, in the middle-resistance portion, as seen in the buckling direction.

[Claim 3] The probe according to claim 2, wherein

the high-resistance portion of the middle-high resistance portion is formed in a recess formed on at least one of the side surfaces in the buckling direction of the middle-resistance portion.

[Claim 4] The probe according to any one of claims 1 to 3, wherein

the first metal is one of gold, silver, or copper,

the second metal is a Pd-Co alloy, and

the third metal is a Ni-B alloy.

[Claim 5] A probe card comprising:

a plurality of the probes according to claim 4; and

at least two guides each having a plurality of guide holes in which the probes are respectively inserted so as to be guided, wherein

the middle-high resistance portions are inserted in the guide holes of the guide located closest to the contact portion side.